

**IN THE CLAIMS**

Please amend the claims as follows:

Claim 1 (currently amended): A package substrate comprising:

an outermost interlayer resin insulating layer;

a pad structure formed on the outermost interlayer resin insulating layer;

a solder resist formed on the outermost interlayer resin insulating layer and the pad structure, the solder resist having an opening exposing a partially exposed portion of the pad structure;

a conductive connecting pin configured to establish an electrical connection with another substrate, the conductive connecting pin being secured to the partially exposed portion of the pad structure via a solder, the solder being disposed over at least one metal layer formed in the partially exposed portion of the pad structure; and

a via hole formed through the outermost interlayer resin insulating layer and configured to electrically connect the pad structure to at least one conductive circuit formed below the outermost interlayer resin insulating layer, the via hole being positioned directly below the pad structure,

wherein the at least one metal layer is formed in the partially exposed portion of the pad structure after the opening is formed in the solder resist.

Claims 2-89 (canceled)

Claim 90 (previously presented): The package structure according to claim 1, further comprising:

at least one conductor layer comprising a plurality of conductor circuits formed below the outermost interlayer resin insulating layer; and

at least one interlayer resin insulating layer formed below the conductor layer, wherein the conductor layer and the interlayer resin insulating layer are alternately formed.

Claim 91 (previously presented): The package structure according to claim 1, wherein the pad structure comprises an outermost conductor portion formed on the outermost interlayer resin insulating layer.

Claim 92 (previously presented): The package structure according to claim 1, wherein the pad structure comprises an outermost conductor portion formed on the outermost interlayer resin insulating layer and the at least one conductor circuit is positioned directly below the pad structure.

Claim 93 (previously presented): The package structure according to claim 90, wherein the pad structure comprises an outermost conductor portion formed on the outermost interlayer resin insulating layer and the at least one conductor circuit is positioned directly below the pad structure.

Claim 94 (previously presented): The package structure according to claim 90, further comprises at least one lower via hole directly connected to the via hole and formed through the at least one interlayer resin insulating layer formed below the conductor layer, the at least one lower via hole being configured to electrically connect the via hole to at least one of the conductor circuits in the at least one conductor layer.

Claim 95 (previously presented): The package structure according to claim 1, wherein the pad structure comprises a plane layer.

Claim 96 (previously presented): The package structure according to claim 1, further comprising a signal line formed on the outermost interlayer resin insulating layer, wherein the signal line connects to the pad structure, and the signal line is covered with the solder resist.

Claim 97 (previously presented): The package structure according to claim 1, wherein a diameter of the pad structure is 1.02 times to 100 times a diameter of the opening.

Claim 98 (previously presented): The package structure according to claim 1, wherein the conductive connecting pin comprises a columnar connection portion and a plate-

like secured portion, the secured portion is secured to the pad through the solder, and the conductive connecting pin comprises at least one of Cu, a copper alloy, Ti, Zn, Al and a noble metal.

Claim 99 (previously presented): The package structure according to claim 98, wherein the columnar connection portion has a constriction portion having a diameter which is smaller than a diameter of other portion.

Claim 100 (previously presented): The package structure according to claim 1, wherein the pad structure has a roughened surface.

Claim 101 (previously presented): The package structure according to claim 92, wherein the pad structure has a roughened surface.

Claim 102 (previously presented): The package structure according to claim 94, wherein the pad structure has a roughened surface.

Claim 103 (currently amended): A package substrate comprising:  
an outermost interlayer resin insulating layer;  
a pad structure formed on the outermost interlayer resin insulating layer;  
a solder resist formed on the outermost interlayer resin insulating layer and the pad structure, the solder resist having an opening exposing a partially exposed portion of the pad structure;

conductive connecting means for establishing an electrical connection with another substrate, the conductive connecting means being secured to the partially exposed portion of the pad structure via solder, the solder being disposed over at least one metal layer formed in the partially exposed portion of the pad structure; and

a via hole formed through the outermost interlayer resin insulating layer and configured to electrically connect the pad structure to at least one conductive circuit formed

below the outermost interlayer resin insulating layer, the via hole being positioned directly below the pad structure,

wherein the at least one metal layer is formed in the partially exposed portion of the pad structure after the opening is formed in the solder resist.

Claim 104 (previously presented): The package structure according to claim 103, further comprising:

at least one conductor layer comprising a plurality of conductor circuits formed below the outermost interlayer resin insulating layer; and

at least one interlayer resin insulating layer formed below the conductor layer, wherein the conductor layer and the interlayer resin insulating layer are alternately formed.

Claim 105 (previously presented): The package structure according to claim 103, wherein the pad structure comprises an outermost conductor portion formed on the outermost interlayer resin insulating layer.

Claim 106 (previously presented): The package structure according to claim 103, wherein the pad structure comprises an outermost conductor portion formed on the outermost interlayer resin insulating layer and the at least one conductor circuit is positioned directly below the pad structure.

Claim 107 (previously presented): The package structure according to claim 104, wherein the pad structure comprises an outermost conductor portion formed on the outermost interlayer resin insulating layer and the at least one conductor circuit is positioned directly below the pad structure.

Claim 108 (previously presented): The package structure according to claim 104, further comprises at least one lower via hole directly connected to the via hole and formed through the at least one interlayer resin insulating layer formed below the conductor layer, the

at least one lower via hole being configured to electrically connect the via hole to at least one of the conductor circuits in the at least one conductor layer.

Claim 109 (previously presented): The package structure according to claim 103, wherein the pad structure comprises a plane layer.

Claim 110 (previously presented): The package structure according to claim 103, further comprising a signal line formed on the outermost interlayer resin insulating layer, wherein the signal line connects to the pad structure, and the signal line is covered with the solder resist.

Claim 111 (previously presented): The package structure according to claim 103, wherein a diameter of the pad structure is 1.02 times to 100 times a diameter of the opening.

Claim 112 (previously presented): The package structure according to claim 103, wherein the conductive connecting means comprises at least one of Cu, a copper alloy, Ti, Zn, Al and a noble metal.

Claim 113 (previously presented): The package structure according to claim 103, wherein the pad structure has a roughened surface.

Claim 114 (previously presented): The package structure according to claim 106, wherein the pad structure has a roughened surface.

Claim 115 (previously presented): The package structure according to claim 108, wherein the pad structure has a roughened surface.

Claim 116 (previously presented): The package structure according to claim 1, wherein the at least one metal layer formed in the partially exposed portion of the pad structure comprises a plurality of metal layers.

Claim 117 (previously presented): The package structure according to claim 1, wherein the at least one metal layer formed in the partially exposed portion of the pad structure comprises at least one metal which prevents corrosion.

Claim 118 (previously presented): The package structure according to claim 1, wherein the at least one metal layer formed in the partially exposed portion of the pad structure comprises at least one material selected from the group consisting of gold, silver, copper, nickel, tin, aluminum, lead, phosphorus, chrome, tungsten, molybdenum, titanium, platinum and solder.

Claim 119 (previously presented): The package structure according to claim 103, wherein the at least one metal layer formed in the partially exposed portion of the pad structure comprises a plurality of metal layers.

Claim 120 (previously presented): The package structure according to claim 103, wherein the at least one metal layer formed in the partially exposed portion of the pad structure comprises at least one metal which prevents corrosion.

Claim 121 (previously presented): The package structure according to claim 103, wherein the at least one metal layer formed in the partially exposed portion of the pad structure comprises at least one material selected from the group consisting of gold, silver, copper, nickel, tin, aluminum, lead, phosphorus, chrome, tungsten, molybdenum, titanium, platinum and solder.